

Notice of References Cited

Application/Control No.

10/064,721

Applicant(s)/Patent Under
Reexamination
DEWANJEE, PIJUSH K.

Examiner

David Buttner

Art Unit

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Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0064826	04-2003	Voorheis et al.	473/367
	B	US-6,486,261	11-2002	Wu et al.	525/332.6
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chemical Abstract registry # 101-96-2
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